

Workshop in Application of Standards within Nanometrology, June 2nd 2009

Chairman: Dr James Johnstone, The Nanotechnology Knowledge Transfer Network, UK

Programme:

9:30 Opening remarks by Chairman

9:40 Keynote Speaker:

Dr Steffi Friedrichs, Nanotechnology Industry Association, Belgium

Title: The Importance of Standards to the Nanotechnology Industries

10:10 Dr Gert Roebben, Institute for Reference Materials and Measurements, Belgium

Title: Application of Documentary Standards in the Characterisation of Manufactured Nanoparticles

10:40 Dr Wolfgang Unger, Federal Institute for Materials Research and Testing, Germany

Title: Metrological Challenges in Surface Nano Analysis

11:00 Coffee/Tea break

11:30 Dr Hermann Stamm, Institute for Health and Consumer Protection, Italy

Title: Nanosafety Measurements and Testing: Standardisation and Harmonisation Needs

12:00 Thorsten Dziomba, Physikalisch-Technische Bundesanstalt (PTB), Germany

Title: Standards for Scanning Probe Microscopy

12:30 Round Table Discussion

12:55 Closing remarks by Chairman

13:00 End